L Number	Hits	Search Text	DB	Time stamp
2	585810	substrate or wafer	EPO; JPO; IBM_TDB	2004/02/23 15:36
3	1577	(dut or (device adj under adj test))	EPO; JPO; IBM_TDB	2004/02/23 15:36
1	1	((interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test)))) and (substrate or wafer)	EPO; JPO; IBM_TDB	2004/02/23 15:37
4	30	(interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test)))	EPO; JPO; IBM_TDB	2004/02/23 15:37
-	375	(356/477).CCLS.	USPAT; US-PGPUB	2004/02/19 15:54
-	973	(356/73.1).CCLS.	USPAT; US-PGPUB	2004/02/19 15:54
-	1074	(385/12).CCLS.	USPAT; US-PGPUB	2004/02/23 12:20
-	9	385/12.ccls. and (dut or (device adj under adj test))	USPAT; US-PGPUB	2004/02/23 12:21
-	6214	(dut or (device adj under adj test))	USPAT; US-PGPUB	2004/02/23 15:36
-	555755	interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric	USPAT; US-PGPUB	2004/02/23 12:22
-	1311	(interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test)))	USPAT; US-PGPUB	2004/02/23 15:36
-	648590	substrate or wafer	USPAT; US-PGPUB	2004/02/23 15:36
-	605	((interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test)))) and (substrate or wafer)	USPAT; US-PGPUB	2004/02/23 15:36
-	25	356/$.ccls. and (((interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test)))) and (substrate or wafer))	USPAT; US-PGPUB	2004/02/23 13:18
-	109	356/$.ccls. and ((interfer or interfere or interference or interfering or interferometer or interferometrically or interferometric) and ((dut or (device adj under adj test))))	USPAT; US-PGPUB	2004/02/23 13:19